Assessing Capability with Non-Normal Data — Distribution Fitting

Data Science for Quality Management: Process Capability

with Wendy Martin

Learning objective:

Assess capability / performance from a non normal distribution with fitted data

Step 6 — Assess Process Control

 We will use the Map Sensor data to demonstrate calculating process capability using distribution fitting.

Process Capability Distribution Fitting

The MAP Sensor Problem:

• A major automobile manufacturer produces a Manifold Absolute Pressure Sensor (MAP) Sensor, an electronic device that links the Powertrain Control Module with the engine in all its automobiles.

Process Capability Distribution Fitting

- Inside this sensor is a ceramic substrate, with surface mounted components.
- The placement of these components is critical, and their location is measured from datum reference points in the X, Y, and Z axes.

Process Capability Distribution Fitting

- The data file mapsensor dat contains the z-axis values for one of the critical components; from 50 consecutive production lots.
- The specification for this component is 0.9500+/-0.4000 (coded data in thousandths of an inch)

Best Distribution Fit

- Best fit from available distributions is the distribution with:
 - Lowest AIC value
 - Best fit in the tail regions in plots

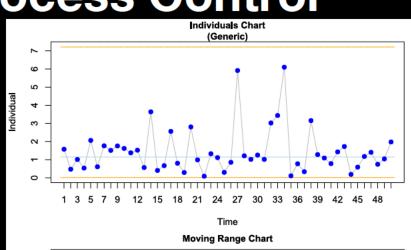
Best Distribution Fit

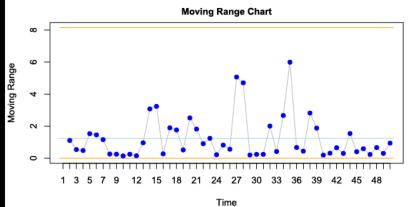
Distribution	LPL	UPL	AIC	Other
Exponential	0.002	9.644	139.81	
Weibull	0.009	6.913	136.89	
Gamma	0.021	7.213	135.31	
Log Normal	0.076	14.418	136.99	
Johnson	-1.908	12.687	147.71	

Step 6 — Assess Process Control

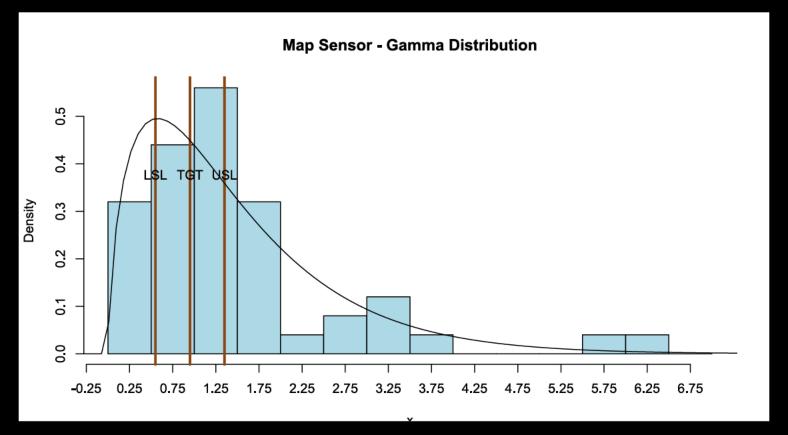
Control Chart with Gamma distribution for the individuals, Exponential distribution for moving range

```
spc.chart.variables.individual.and.movingrange.
generic.simple(individuals = mapsensor$z_axis
,chart1.center.line = median(mapsensor$z_axis)
,chart1.control.limits.lcl = LNPL.gamma
,chart1.control.limits.ucl = UNPL.gamma
,chart2.control.limits.lcl = LNPL.mr.exp
,chart2.control.limits.ucl = UNPL.mr.exp)
```





Gamma Distribution



Send data to an object named "data"
data<-mapsensor\$z_axis</pre>

```
# Goodness of fit for the Gamma
fit.g<-fitdist(data = mapsensor$z_axis, distr
= "gamma")
shape<-fit.g$estimate[1]
rate<-fit.g$estimate[2]</pre>
```

```
# Get natural tolerance for the Gamma
Distribution for the individual values
f<-function(p,lower.tail)</pre>
{qgamma(p, shape = shape, rate = rate,
lower.tail = lower.tail)
nt.gamma<-natural.tolerance(f)</pre>
```

```
# Define inputs
LSL <- 0.55
Target <- 0.95
USL <- 1.35
```

```
# Define inputs - proportion out of spec
l.out <- pgamma(q = LSL, shape = shape, rate
= rate, lower.tail = T)
u.out <- pgamma(q = USL, shape = shape, rate
= rate, lower.tail = F)
total.out <- l.out + u.out</pre>
```

```
# Define inputs - Actual out of spec
obs.above.spec <- sum(data > USL)
obs.below.spec <- sum(data < LSL)
totaln <- length(data)</pre>
```

```
spc.capability.summary.ungrouped.nonnormal.si
mple.R()
```

Sources

The material used in the PowerPoint presentations associated with this course was drawn from a number of sources. Specifically, much of the content included was adopted or adapted from the following previously-published material:

- Luftig, J. An Introduction to Statistical Process Control & Capability. Luftig & Associates, Inc. Farmington Hills, MI, 1982
- Luftig, J. Advanced Statistical Process Control & Capability. Luftig & Associates, Inc. Farmington Hills, MI, 1984.
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- Luftig, J. Guidelines for Reporting the Capability of Critical Product Characteristics. Anheuser-Busch Companies, St. Louis, MO. 1994
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- Luftig, J. and Petrovich, M. Quality with Confidence in Manufacturing. SPSS, Inc. Chicago, IL 1997
- Littlejohn, R., Ouellette, S., & Petrovich, M. Black Belt Business Improvement Specialist Training, Luftig & Warren International, 2000
- Ouellette, S. Six Sigma Champion Training, ROI Alliance, LLC & Luftig & Warren, International, Southfield, MI 2005